

Carl Zeiss NTS, LLC

More than 160 years of experience in optics has laid the foundation for pioneering electron and ion beam microscopes from Carl Zeiss Nano Technology Systems. Based on a broad technology portfolio, we are an innovation leader in the field of particle beam-based imaging, inspection, analysis, and measuring systems. Products comprise scanning and transmission electron microscopes (SEM/TEM) with ultra-high resolution, superior analytical capabilities, and unrivaled contrast, complemented by CrossBeam® (FIB-SEM) technology designed for sub-surface 3D volumetric characterization. The unique ORION® Helium-Ion technology offers unrivaled opportunities for sub-nanometer imaging, depth-of-focus capabilities, and new image contrast features. With the Shuttle & Find interface for Correlative Microscopy, we are crossing the boundaries between light and electron microscopy—allowing seamless integration of these two complementary technologies.

Our mission at all times: Maximum Information—Maximum Insight.

- **EVO® HD** – SEM offering unique High Definition imaging with an analytical platform and Environmental SEM capabilities.
- **SIGMA VP** – Versatile FESEM providing unrivaled ease of use; enabling imaging and analysis of nonconductive specimen.
- **MERLIN** – The ZEISS FE-SEM flagship MERLIN offers unprecedented probe current and ultra fast detection technology for high-throughput imaging of large fields of view and unsurpassed analytical capabilities.
- **AURIGA** – Designed for sub-surface 3D volumetric characterization, AURIGA is the very analytical tool for advanced research in Materials Analysis as well as Life Science applications.
- **ORION** – Based on the unique Helium Ion technology, ORION is the next-generation workstation for nanoscale research.
- **LIBRA 120 PLUS** – Designed to be a highly versatile analytical TEM workhorse, LIBRA 120 excels through class-leading image contrast, high throughput, and superior imaging of beam sensitive and frozen hydrated samples.
- **LIBRA 200 CS-TEM/CS-STEM** – As the ultimate research tool, LIBRA 200 CS-TEM/CS-STEM provides a “Corrected View of the Sub-Ångstrom World,” thanks to aberration corrector for the illumination system and imaging corrector for the objective lens.

Focused on the needs of research and development as well as production processes and technologies in Materials Research, Life Sciences, Quality Control, and Natural Resources, we are serving a wide variety of industries and research institutes in academia and industry around the globe.



We make it visible.



How to find us

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